

Supplementary Information for :

## Highly robust SiCOH/mesoporous SiO<sub>2</sub> ultralow dielectric films with heterostructures

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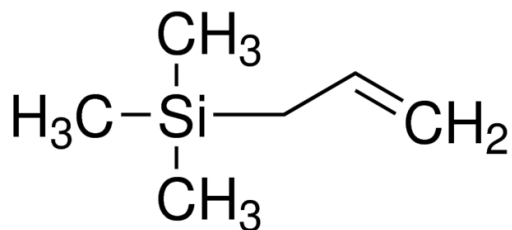
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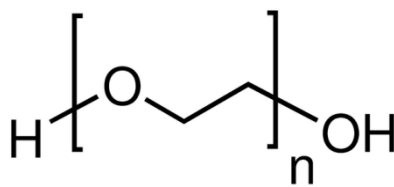
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**ATMS (top matrix)**



**PEG (porogen)**



**SBA-15 (bottom matrix)**

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**Fig. S1.** Molecular structure of ATMS, PEG, and SBA-15 used as the matrix and labile phase source, respectively.

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**Table S1.** Properties of mesoporous SiO<sub>2</sub> powders.

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Type	Size (nm)	Pore size (nm)	Surface area (m <sup>2</sup> /g)
<b>SBA-15</b>	-	<b>7.4</b>	<b>802</b>
MCM41	4.5 ~ 4.8	2.1~2.7	1000
Porous SiO <sub>2</sub>	5 ~ 15	Spherical	590 ~ 690
SiO <sub>2</sub> nanopowder	12	-	175~225

**Table S2.** Mechanical properties of mesoporous SiO<sub>2</sub>/PEG composite films.

Materials	Modulus (GPa)	Hardness (GPa)
<b>SBA-15/PEG</b>	<b>2.93</b>	<b>0.10</b>
MCM41/PEG	1.42	0.07
Porous SiO <sub>2</sub> /PEG	1.85	0.04
SiO <sub>2</sub> nanopowder/PEG	4.04	0.05

10 SBA-15 has high modulus and hardness among mesoporous silicas with high surface area (~800 m<sup>2</sup>/g). We selected SBA-15/PEG as a buffer layer of SiCOH/mesoporous SiO<sub>2</sub> composite films for this reason.

**Table S3.** A comparison table between this study and previously reported dielectric constants and moduli of 10 low-k SiCOH films.<sup>33-37,48-51</sup>

Dielectric constant	Modulus [GPa]	Ref.
2.6	6.4	Jousseaume et al., <i>J. Electrochem. Soc.</i> , 2007.
2.4	3.5	Burkey et al., <i>J. Electrochem. Soc.</i> , 2004.
2.4	9	Frot et al., <i>Adv. Funct. Mater.</i> , 2012.
<b>2.4</b>	<b>8.4</b>	<b>Park et al., <i>J. Mater. Chem. C</i>, 2013.</b>
2.3	5.9	Rathore et al., <i>Adv. Funct. Mater.</i> , 2008.
2.3	4.1	Dubois et al., <i>Proc. IEEE Int. Interconnect Technol. Conf.</i> , 2005.
2.2	6~7	Eslava et al., <i>J. Am. Chem. Soc.</i> , 2008.
2.2	5.4	Trujillo et al., <i>Adv. Funct. Mater.</i> , 2010.

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*This work*